Application/Control No.	Applicant(s)/Patent under Reexamination
10/642,914	FAN ET AL.
Examiner	Art Unit
Charles Kim	2624

SEARCHED					
Class	Subclass	Date	Examiner		
-					

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
See search history report	1/11/2007	ск
IEEE Search	1/11/2007	ск
Inventor name search	1/11/2007	СК